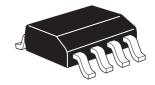


ZXMN6A09DN8 60V SO8 N-channel enhancement mode MOSFET

Summary

V _{(BR)DSS}	$R_{DS(on)}\left(\Omega\right)$	I _D (A)
60	0.040 @ V _{GS} = 10V	5.6
	0.060 @ V _{GS} = 4.5V	4.6



Description

This new generation of trench MOSFETs from Zetex utilizes a unique structure that combines the benefits of low on-resistance with fast switching speed. This makes them ideal for high efficiency, low voltage power management applications.

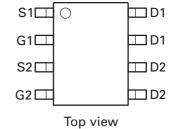
Features

- · Low on-resistance
- · Fast switching speed
- · Low threshold
- · Low gate drive
- · SOIC package

G1 G2 D2 S2 S2

Applications

- DC-DC converters
- · Power management functions
- Disconnect switches
- · Motor control



Ordering information

Device	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXMN6A09DN8TA	7	12	500

Device marking

ZXMN 6A09D

Absolute maximum ratings

Parameter	Symbol	Limit	Unit
Drain-source voltage	V _{DSS}	60	V
Gate-source voltage	V _{GS}	±20	V
Continuous drain current @ V _{GS} =10V; T _{amb} =25°C ^(b)	I _D	5.6	Α
@ V _{GS} =10V; T _{amb} =70°C ^(b)		4.5	
@ V _{GS} =10V; T _{amb} =25°C ^(a)		4.3	
Pulsed drain current ^(c)	I _{DM}	27	Α
Continuous source current (body diode)(b)	I _S	3.5	Α
Pulsed source current (body diode)(c)	I _{SM}	27	А
Power dissipation at $T_{amb} = 25^{\circ}C^{(a)(d)}$	P_{D}	1.25	W
Linear derating factor		10	mW/°C
Power dissipation at $T_{amb} = 25^{\circ}C^{(b)(e)}$	P_{D}	1.8	W
Linear derating factor		14	mW/°C
Power dissipation at $T_{amb} = 25^{\circ}C^{(b)(d)}$	P _D	2.1	W
Linear derating factor		17	mW/°C
Operating and storage temperature range	T _j , T _{stg}	-55 to +150	°C

Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient ^{(a)(d)}	$R_{\Theta JA}$	100	°C/W
Junction to ambient ^{(a)(e)}	$R_{\Theta JA}$	70	°C/W
Junction to ambient ^{(b)(d)}	$R_{\Theta JA}$	60	°C/W

NOTES:

⁽a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

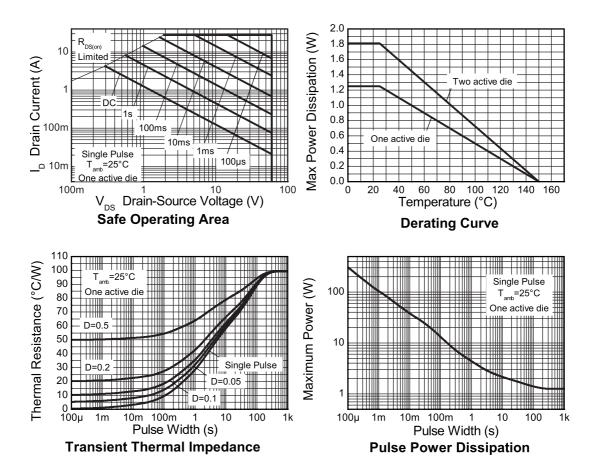
⁽b) For a device surface mounted on FR4 PCB measured at t \leq 10 sec.

⁽c) Repetitive rating - 25mm x 25mm FR4 PCB, D=0.02, pulse width $300\mu s$ - pulse width limited by maximum junction temperature.

⁽d) For a dual device with one active die.

⁽e) For a device with two active die running at equal power.

Characteristics



Electrical characteristics (at T_{amb} = 25°C unless otherwise stated)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions	
Static		'					
Drain-source breakdown voltage	V _{(BR)DSS}	60			V	I _D = 250μA, V _{GS} =0V	
Zero gate voltage drain current	I _{DSS}			1	μΑ	V _{DS} = 60V, V _{GS} =0V	
Gate-body leakage	I _{GSS}			100	nA	V _{GS} =±20V, V _{DS} =0V	
Gate-source threshold voltage	V _{GS(th)}	1.0		3.0	V	$I_D=250\mu A, V_{DS}=V_{GS}$	
Static drain-source on-state	R _{DS(on)}			0.040	Ω	V _{GS} = 10V, I _D = 8.2A	
resistance ^(*)				0.060	Ω	$V_{GS} = 4.5V, I_D = 7.4A$	
Forward transconductance(*)(‡)	9 _{fs}		15		S	V _{DS} = 15V, I _D = 8.2A	
Dynamic ^(‡)		'					
Input capacitance	C _{iss}		1407		pF	V _{DS} = 40V, V _{GS} =0V	
Output capacitance	C _{oss}		121		pF	f=1MHz	
Reverse transfer capacitance	C _{rss}		59		pF		
Switching (†) (‡)		.l	!	!			
Turn-on-delay time	t _{d(on)}		4.9		ns	V _{DD} = 15V, I _D = 3.5A	
Rise time	t _r		5.0		ns	$R_{G} \approx 6.0 \Omega$, $V_{GS} = 10 V$	
Turn-off delay time	t _{d(off)}		25.3		ns		
Fall time	t _f		4.6		ns		
Total gate charge	Q_g		12.4		nC	V _{DS} = 15V, V _{GS} = 5V I _D = 3.5A	
Total gate charge	Qg		24.2		nC	V _{DS} = 15V, V _{GS} = 5V	
Gate-source charge	O _{gs}		5.2		nC	I _D = 3.5A	
Gate drain charge	Q_{gd}		3.5		nC		
Source-drain diode		'					
Diode forward voltage ^(*)	V_{SD}		0.85	0.95	V	T _j =25°C, I _S = 6.6A, V _{GS} =0V	
Reverse recovery time ^(‡)	t _{rr}		26.3		ns	T _j =25°C, I _S = 3.5A,	
Reverse recovery charge ^(‡)	Q _{rr}		26.6		nC	di/dt=100A/μs	

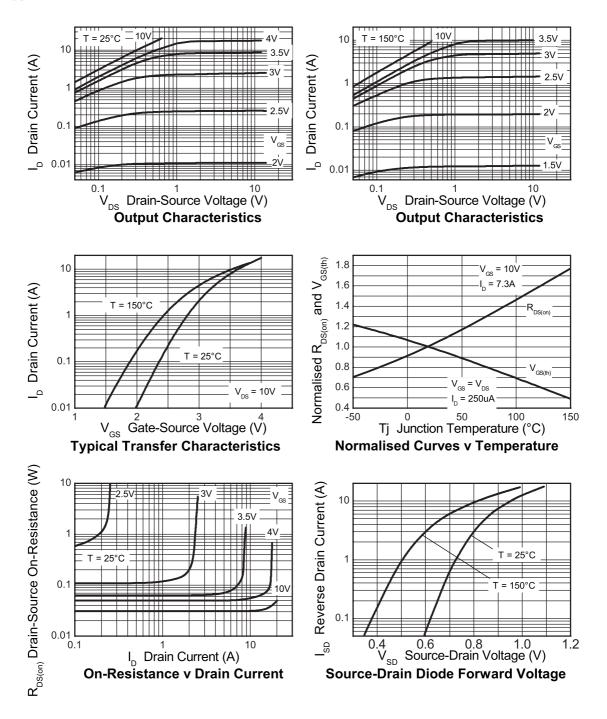
NOTES:

^(*) Measured under pulsed conditions. Pulse width \leq 300 s; duty cycle \leq 2%.

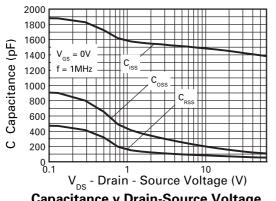
^(†) Switching characteristics are independent of operating junction temperature.

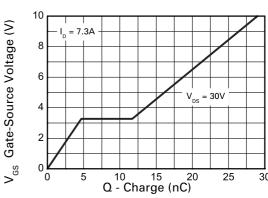
^(‡) For design aid only, not subject to production testing.

Typical characteristics



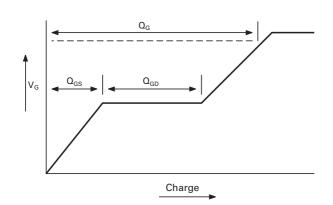
Typical characteristics

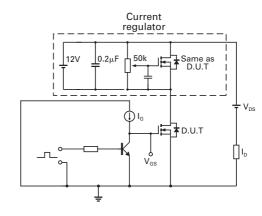




Capacitance v Drain-Source Voltage

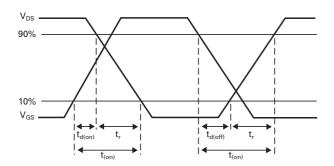
Gate-Source Voltage v Gate Charge

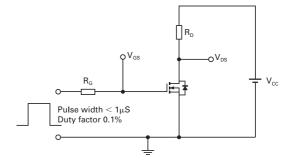




Basic gate charge waveform

Gate charge test circuit

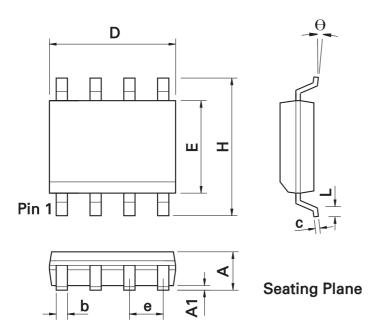




Switching time waveforms

Switching time test circuit

Package outline - SO8



DIM	Inc	hes	Millin	neters	DIM	Inches		Millimeters	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
Α	0.053	0.069	1.35	1.75	е	0.050 BSC		1.27 BSC	
A1	0.004	0.010	0.10	0.25	b	0.013	0.020	0.33	0.51
D	0.189	0.197	4.80	5.00	С	0.008	0.010	0.19	0.25
Н	0.228	0.244	5.80	6.20	θ	0°	8°	0°	8°
Е	0.150	0.157	3.80	4.00	h	0.010	0.020	0.25	0.50
L	0.016	0.050	0.40	1.27	-	-	-	-	-

Note: Controlling dimensions are in inches. Approximate dimensions are provided in millimeters

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